## <u>AMENDMENTS</u>

## In the Claims

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Currently amended) A mechanism for preventing ESD damage to a electronic device comprising at least one connection area having a plurality of pads ( $P_1$  to  $P_n$ ) arranged sequentially for mounting to an integrated circuit, and a plurality of fan-out signal lines ( $F_1$  to  $F_n$ ) extending from the pads ( $P_1$  to  $P_n$ ) respectively, the pads  $P_1$  and  $P_n$  disposed on outermost sides of the connection area, the mechanism comprising:

a plurality of ESD protection device (ES<sub>1</sub> to ES<sub>n</sub>) configured corresponding to the fan-out signal lines (F<sub>1</sub> to F<sub>n</sub>);

wherein, equivalent impedances of the ESD protection devices ES<sub>1</sub> and ES<sub>n</sub> are smaller than equivalent impedances of the other ESD protection devices ES<sub>2</sub> to ES<sub>n-1</sub>.

- 2. (Original) The mechanism as claimed in claim 1, wherein each ESD protection device comprises at least one element having a MOS transistor circuit structure and equivalent channel widths of the ESD protection devices ES<sub>1</sub> and ES<sub>n</sub> are longer than equivalent channel widths of the other ESD protection devices ES<sub>2</sub> to ES<sub>n-1</sub>.
- 3. (Currently amended) A mechanism for preventing ESD damage to a electronic device comprising at least one connection area having a plurality of pads ( $P_1$  to  $P_n$ ) arranged sequentially for mounting to an integrated circuit, and a plurality of fan-out signal lines ( $F_1$  to  $F_n$ ) extending

from the pads (P<sub>1</sub> to P<sub>n</sub>) respectively, the pads P<sub>1</sub> and P<sub>n</sub> disposed on outermost sides of the connection area, the mechanism comprising:

a plurality of ESD protection device (ES<sub>1</sub> to ES<sub>n</sub>) configured corresponding to the fan-out signal lines  $(F_1 \text{ to } F_n)$ ;

wherein, equivalent impedances of the ESD protection devices ES1 to ES, gradually increase and equivalent impedances of the ESD protection devices ESi+1 to ESn gradually decrease, 1 < j < n.

- 4. (Original) The mechanism as claimed in claim 3, wherein each ESD protection device comprises at least one element having a MOS transistor circuit structure, equivalent channel widths of the ESD protection devices ES1 to ES; gradually decrease, and equivalent channel widths of the ESD protection devices ESi+1 to ESn gradually increase.
- 5. (Currently amended) A mechanism for preventing ESD damage to a electronic device comprising at least one connection area having a plurality of pads (P<sub>1</sub> to P<sub>n</sub>) arranged sequentially for mounting to an integrated circuit, and a plurality of fan-out signal lines (F<sub>1</sub> to F<sub>n</sub>) extending from the pads (P<sub>1</sub> to P<sub>n</sub>) respectively, the pads P<sub>1</sub> and P<sub>n</sub> disposed on outermost sides of the connection area, the mechanism comprising:

a plurality of ESD protection device (ES1 to ESn) configured corresponding to the fan-out signal lines  $(F_1 \text{ to } F_n)$ ;

wherein, an equivalent impedance of one ESD protection device ESk is different from equivalent impedances of the other ESD protection devices,  $1 \le k \le n$ 

6. (Original) The mechanism as claimed in claim 5, wherein each ESD protection device comprises at least one element having a MOS transistor circuit structure and an equivalent channel width of the ESD protection device ES<sub>k</sub> is different from equivalent channel widths of the other ESD protection devices.

- 7. (Currently amended) A liquid crystal display panel, comprising:
- a pixel array;

at least one connection area having a plurality of pads  $(P_1 \text{ to } P_n)$  arranged sequentially for mounting to an integrated circuit, wherein the pads  $P_1$  and  $P_n$  are disposed on outermost sides of the connection area;

a plurality of fan-out signal lines  $(F_1 \text{ to } F_n)$  extending from the pads  $(P_1 \text{ to } P_n)$  respectively; and

a plurality of ESD protection devices (ES<sub>1</sub> to ES<sub>n</sub>) configured corresponding to the fanout signal lines ( $F_1$  to  $F_n$ );

wherein, equivalent impedances of the ESD protection devices ES<sub>1</sub> and ES<sub>n</sub> are smaller than equivalent impedances of the other ESD protection devices ES<sub>2</sub> to ES<sub>n-1</sub>.

8. (Original) The liquid crystal display panel as claimed in claim 7, wherein each ESD protection device comprises at least one element having a MOS transistor circuit structure and equivalent channel widths of the ESD protection devices ES<sub>1</sub> and ES<sub>n</sub> are longer than equivalent channel widths of the other ESD protection devices ES<sub>2</sub> to ES<sub>n-1</sub>.

9. (Original) The liquid crystal display panel as claimed in claim 8, wherein the equivalent channel widths of the ESD protection devices  $ES_1$  to  $ES_j$  gradually decrease, and the equivalent channel widths of the ESD protection devices  $ES_{j+1}$  to  $ES_n$  gradually increase, 1 < j < n.

10. (Currently amended) A liquid crystal display panel, comprising:
a pixel array;

at least one connection area having a plurality of pads  $(P_1 \text{ to } P_n)$  arranged sequentially for mounting to an integrated circuit, wherein the pads  $P_1$  and  $P_n$  are disposed on outermost sides of the connection area;

a plurality of fan-out signal lines  $(F_1 \text{ to } F_n)$  extending from the pads  $(P_1 \text{ to } P_n)$  respectively; and

a plurality of ESD protection device (ES<sub>1</sub> to ES<sub>n</sub>) configured corresponding to the fan-out signal lines ( $F_1$  to  $F_n$ );

wherein, an equivalent-impedance of one ESD protection device  $ES_k$  is different from equivalent-impedances of the other ESD protection devices,  $1 \le k \le n$ .

11. (Original) The liquid crystal display panel as claimed in claim 10, wherein each ESD protection device comprises at least one element having a MOS transistor circuit structure and an equivalent channel width of the ESD protection device ES<sub>k</sub> is different from equivalent channel widths of the other ESD protection devices.